THERMAL DATA

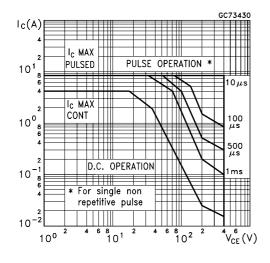
R _{thj-case}	Thermal Resistance Junction-Case	Max	1.78	°C/W
R _{thj-amb}	Thermal Resistance Junction-Ambient	Max	62.5	°C/W

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

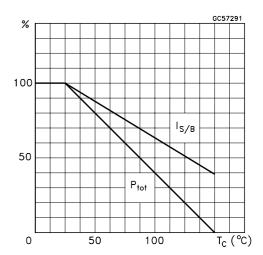
Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
I _{CES}	Collector Cut-off Current (V _{BE} = -1.5 V)	V _{CE} = 700 V V _{CE} = 700 V	T _j = 125 °C			100 500	μA μA
V _{EBO}	Emitter-Base Voltage (I _C = 0)	I _E = 10 mA		9			V
V _{CEO(sus)*}	Collector-Emitter Sustaining Voltage (I _B = 0)	I _C = 100 mA	L = 25 mH	400			V
ICEO	Collector Cut-Off Current (I _B = 0)	V _{CE} = 400 V				250	μА
V _{CE(sat)} *	Collector-Emitter Saturation Voltage	$I_{C} = 0.5 \text{ A}$ $I_{C} = 1 \text{ A}$ $I_{C} = 2.5 \text{ A}$ $I_{C} = 4 \text{ A}$	$I_B = 0.1 A$ $I_B = 0.2 A$ $I_B = 0.5 A$ $I_B = 1 A$		0.5	0.7 1 1.5	V V V
V _{BE(sat)} *	Base-Emitter Saturation Voltage	I _C = 0.5 A I _C = 1 A I _C = 2.5 A	$I_B = 0.1 A$ $I_B = 0.2 A$ $I_B = 0.5 A$			1.1 1.2 1.3	V V V
h _{FE} *	DC Current Gain	I _C = 10 mA I _C = 2 A Group A Group B	V _{CE} = 5 V V _{CE} = 5 V	10 14 25		28 40	
t _s	RESISTIVE LOAD Storage Time Fall Time	$V_{CC} = 125 \text{ V}$ $I_{B1} = 0.4 \text{ A}$ $T_p = 30 \mu\text{s}$	$I_C = 2 A$ $I_{B2} = -0.4 A$ (see fig.2)	1.5	0.2	3 0.4	μs μs
t _s t _f	INDUCTIVE LOAD Storage Time Fall Time	$I_{C} = 2 A$ $V_{BE(off)} = -5 V$ $V_{clamp} = 200 V$	$I_{B1} = 0.4 \text{ A}$ $R_{BB} = 0 \Omega$ (see fig.1)		0.6 0.1	1 0.2	μs μs

* Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %
Note: Product is pre-selected in DC current gain (GROUP A and GROUP B). STMicroelectronics reserves the right to ship either groups according to production availability. Please contact your nearest STMicroelectronics sales office for delivery details.

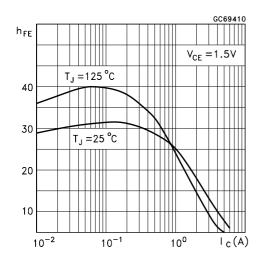
Safe Operating Areas



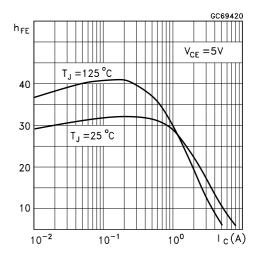
Derating Curve



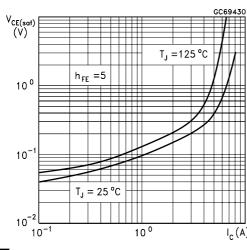
DC Current Gain



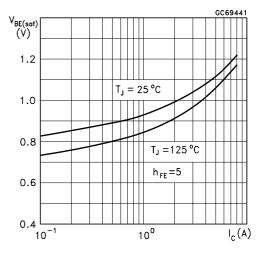
DC Current Gain



Collector Emitter Saturation Voltage

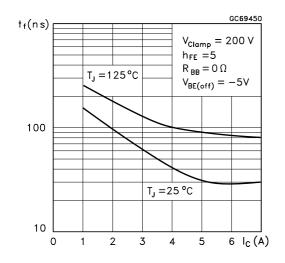


Base Emitter Saturation Voltage

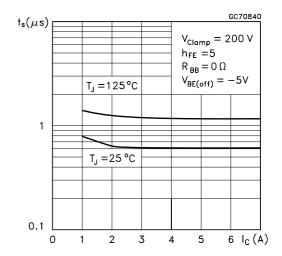


///

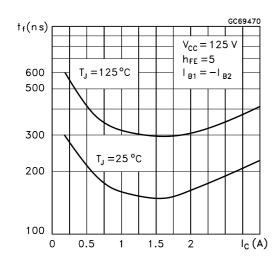
Inductive Load Fall Time



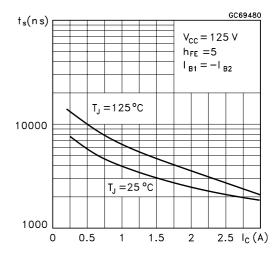
Inductive Load Storage Time



Resistive Load Fall Time



Resistive Load Storage Time



Reverse Biased SOA

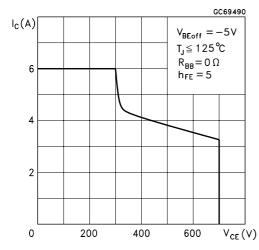


Figure 1: Inductive Load Switching Test Circuit.

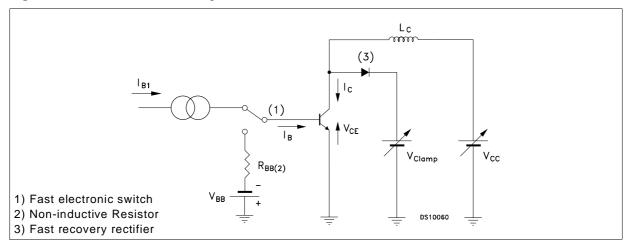
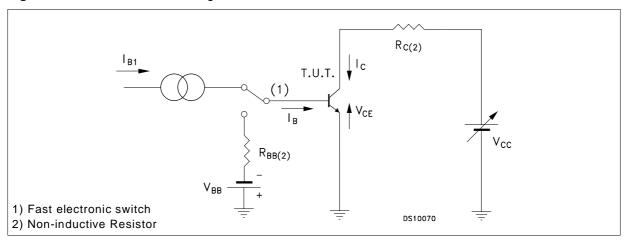
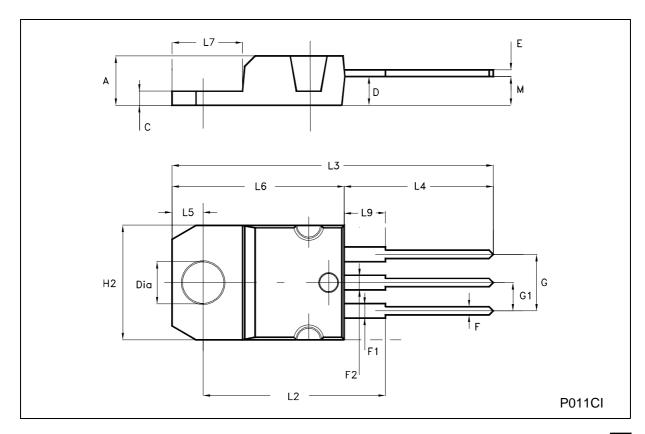


Figure 2: Resistive Load Switching Test Circuit.



TO-220 MECHANICAL DATA

DIM.	mm		inch			
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
С	1.23		1.32	0.048		0.052
D	2.40		2.72	0.094		0.107
Е	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.202
G1	2.40		2.70	0.094		0.106
H2	10.00		10.40	0.394		0.409
L2		16.40			0.645	
L4	13.00		14.00	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.20		6.60	0.244		0.260
L9	3.50		3.93	0.137		0.154
М		2.60			0.102	
DIA.	3.75		3.85	0.147		0.151



Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specification mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a trademark of STMicroelectronics

© 2001 STMicroelectronics – Printed in Italy – All Rights Reserved STMicroelectronics GROUP OF COMPANIES

Australia - Brazil - Canada - China - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States.

http://www.st.com

47/